

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-1027-02		SERIAL NO. 10/774, 371	
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Y. TAKAHASHI et al			
(1) of (2)				FILING DATE February 10, 2004		GROUP 1773 1762	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>	
AB	AA	5,738,927	04/1998	Nakamura et al			
	AB	6,080,476	06/2000	Kanbe et al			
	AC	5,815,343	09/1998	Ishikawa et al			
	AD	6,168,861	01/2001	Chen et al			
	AE	5,939,202	08/1999	Ataka et al			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	AL 10-269548	10/9/98	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM					<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	AR	JOURNAL OF MAGNETISM AND MAGNETIC MATERIALS, 152 (1996), "Effects of Pt addition on the magnetic and crystallographic properties of Co-Cr-Pt thin film media", A. Ishikawa et al, pp. 265-273.					
	AS	Nakatani, Y. and Hayashi, N., IEEE Trans. Mag., 34(4), 1998, 1618-1620.					
	AT	Ikeda, Y., Sonobe, Y., Zeltzer, G., Yen, B., Takano, K., Do, H., Fullerton, E., and Rice, P., IEEE Trans. Mag., 37(4), 2001, 1583, 1585.					
EXAMINER				DATE CONSIDERED			
ABR				9-18-05			

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LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i> <u>(2) of (2)</u>				APPLICANT Y. TAKAHASHI et al		FILING DATE 2/10/04	
				GROUP <u>1773</u> <u>1762</u>			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)	
	AA						
	AB						
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	AD						
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FOREIGN PATENT DOCUMENTS							
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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	AO					<input type="checkbox"/> YES	<input type="checkbox"/> NO
	AP					<input type="checkbox"/> YES	<input type="checkbox"/> NO
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, etc.)</i>							
	AR	Lu, B., Klemmer, T., Khisroev, S., Howard, J., Litvinov, D., Roy, A., and Laughlin, D., IEEE Trans. Mag., 37(4), 2001, 1319-1321.					
	AS	Yamanaka, K., Hamamoto, T., Nakano, Y. and Miura, M., IEEE Trans. Mag., 37(4), 2001, 1599-1601.					
	AT	Futamoto, M., Honda, Y., Miyayama, Y., Itoh, K., Ide, H., and Maruyama, Y., IEEE Trans. Mag., 32(5), 1996, 3789-3794.					
EXAMINER <u>AB/Blm</u>				DATE CONSIDERED <u>9-18-05</u>			
<small>* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							